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		U.S.	PATEN	T DOCUMENTS					
Examiner Initials *	U.S.Patent Document Number	- Name of Patente of Cited Do		or Applicant	Date of Publication of Cited Document MM-DD-YYYY		Filing Date if Appropriat		
NAM	5,568,395	Huang			10-22-1996		6-29-1994		
Kran	6,138,267	Murai			10-24-2000		8-18-1998		
WAN	6,029,117	Devgan			2-22-2000		11-3-1997		
								<u>-</u>	
		FOREIC	GN PAT	ENT DOCUMENTS					
Examiner	Foreign Patent Document			Name of Patentee or A	pplicant Date of		Publication of Translation?		
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Examiner Initials *	U.S.Patent Docum Number	ment	Name of Patentee or Applicant of Cited Document		Cited Docum	Date of Publication of Cited Document MM-DD-YYYY		if Appropriate	
Man	6,044,209	Alpert et al.	-		3-28-200	00	9-15-1997		
Kran	5,859,776	Sato et al.			1-12-199	9	8-12-1996		
WIN	5,883,808	Kawarabayas	shi		3-16-199	99	1-29-1997		
Kram	5,764,528	Nakamura			6-9-199	8	6-25-	-1996	
Krgn	5,838,581	Kuroda			11-17-19	98	9-30-1996		
Krace	5,446,674	lkeda et al.			8-29-199	95	6-2-	1993	
Kraw	5,535,133	Petschauer e	et al.	6-		6	2-9-	1995	
KVAK	5,555,506	5,555,506 Petschauer et al.			9-10-1996		2-9-	1995	
KN-M-	5,596,506	Petschauer e	et al.		1-21-199	7	2-9-	1995	
MIN	5,825,661	Drumm			10-20-1998		5-1-	1996	
		FOR	EIGN PAT	ENT DOCUMENTS				***	
Examiner		Patent Document		Name of Patentee or Applicant		Date of I	Publication of Document		
Initials *	Office or Country	Number	Number Date of Cited Docume		NI -		DD-YYYY	Yes/No	
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			OTHER DO	OCUMENTS			-		
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Substitute f r F rm 1449A/PTO (Modified))	Complete if Known					
INFORMATION DISCLOSURE					Application Number	09/823,0	09/823,085			
					Filing Date	March 29	March 29, 2001			
STATEMENT BY APPLICANT					First Named Inventor:	Jingshen	Jingsheng Jason Cong			
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Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when accompleted 2100 item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s); volume-issue number(s), publisher, city and/or country where published								
Kran	A	KAWAGUCHI, H. et al.: "Delay and Noise Formulas for Capacitively Coupled Distributed RC lines", in Proc. Asia and South Pacific Design Automation Conf., pp. 35-43, 1998.								
Man	В	NAKAGAWA, S. et al.: "On-chip Cross Talk Noise Model for Deep-Submicrometer ULSI Interconnect", Hewlett-Packard Journal, vol. 49, pp. 39-45, Aug. 1998.								
Kan	С	STÖHR, T. et al.: "Analysis, Reduction and Avoidance of Crosstalk on VLSI Chips", in Proc. Int. Symp. On Physical Design, pp. 211-218, April 1998.								
MAN	D	VITTAL, A. et al.: "Crosstalk Reduction for VLSI", IEEE Trans. On Computer-aided Design of Integrated Circuits and Systems", vol. 16, pp. 290-98, 1997.								
Kran	E	DEVGAN, A.: "Efficient Coupled Noise Estimation for On-chip Interconnects", in Proc. IEEE/ACM Int. Conf. On Computer Aided Design, pp. 147-153, 1997.								
Kran	F	SEMICONDUCTOR INDUSTRY ASSOCIATION, "The National Technology Roadmap for Semiconductors", 1997 edition.								
Krzk	G	SHEPARD, K.L., et al.: "Noise in Deep Submicron Digital Design", in Proc. IEEE/ACM Int. Conf. On Computer Aided Design, pp. 524-531, 1996.								
fran	Н	SAKURAI, T.: "Closed-form Expressions for Interconnection Delay, Coupling, and Crosstalk in VLSIs", IEEE Trans. On Electron Devices, vol. 40, pp. 118-124, 1993.								
Examiner	λ	MI	7	. []		Date	1110			

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